

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
2				*****
3	*			
4	*			Zvector E6 instruction tests for VRR-h encoded:
5	*			
6	*			E677 VCP - VECTOR COMPARE DECIMAL
7	*			
8	*			James Wekel June 2024
9	*			*****
10				*****
11				*****
12	*			
13	*			basic instruction tests
14	*			
15	*			*****
16	*			This program tests proper functioning of the z/arch E6 VRR-h vector
17	*			compare decimal. Exceptions are not tested.
18	*			
19	*			PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
20	*			obvious coding errors. None of the tests are thorough. They are
21	*			NOT designed to test all aspects of any of the instructions.
22	*			
23	*			*****
24	*			
25	*			*Testcase zvector-e6-15-comparedecimal: VECTOR E6 VRR-h instruction
26	*			
27	*			Zvector E6 tests for VRR-h encoded instruction:
28	*			
29	*			E677 VCP - VECTOR COMPARE DECIMAL
30	*			
31	*			# -----
32	*			# This tests only the basic function of the instruction.
33	*			# Exceptions are NOT tested.
34	*			# -----
35	*			
36	*	main size	2	
37	*	numcpu	1	
38	*	sysclear		
39	*	archlvl	z/Arch	
40	*			
41	*	diag8cmd	enable	# (needed for messages to Hercules console)
42	*	loadcore	"\$(testpath)/zvector-e6-15-comparedecimal.core"	0x0
43	*	diag8cmd	disable	# (reset back to default)
44	*			
45	*			*Done
46	*			
47	*			*****

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
49				*****
50	*			FCHECK Macro - Is a Facility Bit set?
51	*			
52	*			If the facility bit is NOT set, an message is issued and
53	*			the test is skipped.
54	*			
55	*			Fcheck uses R0, R1 and R2
56	*			
57	* eg.			FCHECK 134, 'vector-packed-decimal'
58				*****
59				MACRO
60				FCHECK &BITNO, &NOTSETMSG
61	. *			&BITNO : facility bit number to check
62	. *			&NOTSETMSG : 'facility name'
63	LCLA	&FBBYTE		Facility bit in Byte
64	LCLA	&FBBIT		Facility bit within Byte
65				
66	LCLA	&L(8)		
67	&L(1)	SetA	128, 64, 32, 16, 8, 4, 2, 1	bit positions within byte
68				
69	&FBBYTE	SETA	&BITNO/8	
70	&FBBIT	SETA	&L((&BITNO-(&FBBYTE*8))+1)	
71	. *			MNOTE 0, 'checking Bit=&BITNO: FBBYTE=&FBBYTE, FBBIT=&FBBIT'
72				
73	B	X&SYSNDX		
74	*			Fcheck data area
75	*			skip messgae
76	SKT&SYSNDX DC	C'		Skipping tests:
77	DC	C&NOTSETMSG		
78	DC	C'		facility (bit &BITNO) is not installed.'
79	SKL&SYSNDX EQU	*- SKT&SYSNDX		
80	*			facility bits
81	DS	FD		gap
82	FB&SYSNDX DS	4FD		
83	DS	FD		gap
84	*			
85	X&SYSNDX EQU	*		
86	LA	R0, ((X&SYSNDX- FB&SYSNDX)/8)-1		
87	STFLE	FB&SYSNDX		get facility bits
88				
89	XGR	R0, R0		
90	IC	R0, FB&SYSNDX+&FBBYTE		get fbit byte
91	N	R0, =F' &FBBIT'		is bit set?
92	BNZ	XC&SYSNDX		
93	*			
94	*			facility bit not set, issue message and exit
95	*			
96	LA	R0, SKL&SYSNDX		message length
97	LA	R1, SKT&SYSNDX		message address
98	BAL	R2, MSG		
99				
100	B	EOJ		
101	XC&SYSNDX EQU	*		
102		MEND		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				104 **** 105 * Low core PSWs 106 ****		
00000000	00000000 00000000	00000000 000019FF	108 ZVE6TST	START 0 USING ZVE6TST, R0	Low core addressability	
			109 110			
		00000140 00000000	111 SVOLDPSW EQU	ZVE6TST+X' 140'	z/Arch Supervisor call old PSW	
00000000	00000001 80000000	00000000 000001A0	113	ORG	ZVE6TST+X' 1A0'	z/Architecture RESTART PSW
000001A0	00000001 80000000		114	DC	X' 0000000180000000'	
000001A8	00000000 00000200		115	DC	AD(BEGIN)	
000001B0	00020001 80000000	000001B0 000001D0	117	ORG	ZVE6TST+X' 1D0'	z/Architecture PROGRAM CHECK PSW
000001D0	00020001 80000000		118	DC	X' 0002000180000000'	
000001D8	00000000 0000DEAD		119	DC	AD(X' DEAD')	
000001E0		000001E0 00000200	121 122	ORG	ZVE6TST+X' 200'	Start of actual test program . .

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				124 ****	
				125 * The actual "ZVE6TST" program itself...	
				126 ****	
				127 *	
				128 * Architecture Mode: z/Arch	
				129 * Register Usage:	
				130 *	
				131 * R0 (work)	
				132 * R1-4 (work)	
				133 * R5 Testing control table - current test base	
				134 * R6-R7 (work)	
				135 * R8 First base register	
				136 * R9 Second base register	
				137 * R10 Third base register	
				138 * R11 E6TEST call return	
				139 * R12 E6TESTS register	
				140 * R13 (work)	
				141 * R14 Subroutine call	
				142 * R15 Secondary Subroutine call or work	
				143 *	
				144 ****	
00000200		00000200		146 USING BEGIN, R8	FIRST Base Register
00000200		00001200		147 USING BEGIN+4096, R9	SECOND Base Register
00000200		00002200		148 USING BEGIN+8192, R10	THIRD Base Register
				149	
00000200	0580			150 BEGIN BALR R8, 0	Initialize FIRST base register
00000202	0680			151 BCTR R8, 0	Initialize FIRST base register
00000204	0680			152 BCTR R8, 0	Initialize FIRST base register
				153	
00000206	4190 8800		00000800	154 LA R9, 2048(, R8)	Initialize SECOND base register
0000020A	4190 9800		00000800	155 LA R9, 2048(, R9)	Initialize SECOND base register
				156	
0000020E	41A0 9800		00000800	157 LA R10, 2048(, R9)	Initialize THIRD base register
00000212	41A0 A800		00000800	158 LA R10, 2048(, R10)	Initialize THIRD base register
				159	
00000216	B600 82C4		000004C4	160 STCTL R0, R0, CTLR0	Store CRO to enable AFP
0000021A	9604 82C5		000004C5	161 OI CTLR0+1, X' 04'	Turn on AFP bit
0000021E	9602 82C5		000004C5	162 OI CTLR0+1, X' 02'	Turn on Vector bit
00000222	B700 82C4		000004C4	163 LCTL R0, R0, CTLR0	Reload updated CRO
				164	
				165 ****	
				166 * Is Vector packed-decimal facility installed (bit 134)	
				167 ****	
				168	
00000226	47F0 80B0		000002B0	169 FCHECK 134, 'vector-packed-decimal'	
				170+ B X0001	
				171+*	Fcheck data area
				172+*	skip message
0000022A	40404040 40404040			173+SKT0001 DC C' Skipping tests: '	
00000244	A58583A3 96996097			174+ DC C' vector-packed-decimal'	
00000259	40868183 899389A3	00000054	00000001	175+ DC C' facility (bit 134) is not installed.'	
				176+SKL0001 EQU *- SKT0001	
				177+*	facility bits
00000280	00000000 00000000			178+ DS FD	gap
00000288	00000000 00000000			179+FB0001 DS 4FD	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000002A8	00000000 00000000			180+ 181+*	DS	FD	gap
000002B0	4100 0004	000002B0	00000001	182+X0001	EQU *		
000002B4	B2B0 8088		00000004	183+	LA R0, ((X0001-FB0001)/8)-1		get facility bits
000002B8	B982 0000		00000288	184+	STFLE FB0001		
000002BC	4300 8098		00000298	185+	XGR R0, R0		
000002C0	5400 82CC		000004CC	186+	IC R0, FB0001+16		get fbit byte
000002C4	4770 80D8		000002D8	187+	N R0, =F' 2'		is bit set?
				188+	BNZ XC0001		
				189+*			
				190+* facility bit not set, issue message and exit			
				191+*			
000002C8	4100 0054		00000054	192+	LA R0, SKL0001		message length
000002CC	4110 802A		0000022A	193+	LA R1, SKT0001		message address
000002D0	4520 81E0		000003E0	194+	BAL R2, MSG		
000002D4	47F0 82A8		000004A8	195+	B EOJ		
		000002D8	00000001	196+XC0001	EQU *		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				198 ****			
				199 *			
				Do tests in the E6TESTS table			
				200 ****			
				201			
000002D8	58C0 82D0		000004D0	202 L R12, =A(E6TESTS)		get table of test addresses	
				203			
000002DC	5850 C000	000002DC	00000001	204 NEXTE6 EQU *		get test address	
000002E0	1255		00000000	205 L R5, 0(0, R12)		have a test?	
000002E2	4780 8196		00000396	206 LTR R5, R5			
				207 BZ ENDTEST		done?	
				208			
000002E6	B982 0000			209 XGR R0, R0		no cc error	
				210			
000002EA		00000000		211 USING E6TEST, R5			
				212			
000002EA	58B0 5000		00000000	213 L R11, TSUB		get address of test routine	
000002EE	05BB			214 BALR R11, R11		do test	
				215			
000002F0	E310 5009 0076		00000009	216 LB R1, CCMASK		(failure CC mask)	
000002F6	8910 0004		00000004	217 SLL R1, 4		(shift to BC instr CC position)	
000002FA	4410 8106		00000306	218 EX R1, TESTCC		fail if...	
				219			
000002FE	41C0 C004		00000004	220 LA R12, 4(0, R12)		next test address	
00000302	47F0 80DC		000002DC	221 B NEXTE6			
				222			
00000306	4700 810A		0000030A	223 TESTCC BC 0, CCMMSG		(fail if unexpected condition code)	
				224			

LOC	OBJECT CODE	ADDR1	ADDR2	STM
				226 **** 227 * cc was not as expected
		0000030A	00000001	228 **** 229 CCMMSG EQU * 230 *
				231 * extract CC extracted PSW 232 *
0000030A	5810 8E9C	0000109C	233 L R1, CCPSW	
0000030E	8810 000C	0000000C	234 SRL R1, 12	
00000312	5410 82D4	000004D4	235 N R1, =XL4' 3'	
00000316	4210 8EA4	000010A4	236 STC R1, CCFOUND	save cc
			237 *	
			238 * FILL IN MESSAGE	
			239 *	
0000031A	4820 5004	00000004	240 LH R2, TNUM	get test number and convert
0000031E	4E20 8E89	00001089	241 CVD R2, DECNUM	
00000322	D211 8E73 8E5D	00001073	242 MVC PRT3, EDIT	
00000328	DE11 8E73 8E89	00001073	243 ED PRT3, DECNUM	
0000032E	D202 8E18 8E80	00001018	244 MVC CCPRTNUM(3), PRT3+13	fill in message with test #
		245		
00000334	D207 8E35 500A	00001035	0000000A	fill in message with instruction
		246	MVC CCPRTNAME, OPNAME	
		247		
0000033A	B982 0022		248 XGR R2, R2	get CC as U8
0000033E	4320 5008	00000008	249 IC R2, CC	
00000342	4E20 8E89	00001089	250 CVD R2, DECNUM	and convert
00000346	D211 8E73 8E5D	00001073	251 MVC PRT3, EDIT	
0000034C	DE11 8E73 8E89	00001073	252 ED PRT3, DECNUM	
00000352	D200 8E4B 8E82	0000104B	253 MVC CCPRTEXP(1), PRT3+15	fill in message with CC field
		254		
00000358	B982 0022		255 XGR R2, R2	get CCFOUND as U8
0000035C	4320 8EA4	000010A4	256 IC R2, CCFOUND	
00000360	4E20 8E89	00001089	257 CVD R2, DECNUM	and convert
00000364	D211 8E73 8E5D	00001073	258 MVC PRT3, EDIT	
0000036A	DE11 8E73 8E89	00001073	259 ED PRT3, DECNUM	
00000370	D200 8E5B 8E82	0000105B	260 MVC CCPRTGOT(1), PRT3+15	fill in message with ccfound
		261		
00000376	4100 0055	00000055	262 LA R0, CCPRTLNG	message length
0000037A	4110 8E08	00001008	263 LA R1, CCPRTLINE	message address
0000037E	45F0 81A4	000003A4	264 BAL R15, RPTERROR	
		265		
00000382	47F0 8186	00000386	266 B FAILCONT	
		267		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				268 **** 269 * continue after a failed test 270 ****
00000386	5800 82D8	00000386	00000001	271 FAILCONT EQU *
0000038A	5000 8E00		000004D8	272 L R0, =F' 1' set GLOBAL failed test indicator
0000038E	41C0 C004		00001000	273 ST R0, FAILED
00000392	47F0 80DC		00000004	274
			000002DC	275 LA R12, 4(0, R12) next test address
				276 B NEXTE6
				278 ****
				279 * end of testing; set ending psw 280 ****
00000396	5810 8E00	00000396	00000001	281 ENDTEST EQU *
0000039A	1211		00001000	282 L R1, FAILED did a test fail?
0000039C	4780 82A8		000004A8	283 LTR R1, R1
000003A0	47F0 82C0		000004C0	284 BZ EOJ No, exit
				285 B FAILTEST Yes, exit with BAD PSW
				286

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				288 ****	*****	*****
				289 * RPTERROR	Report instruction test in error	
				290 *	R0 = MESSGAE LENGTH	
				291 *	R1 = ADDRESS OF MESSAGE	
				292 ****	*****	*****
000003A4	50F0 81C4	000003C4	294	RPTERROR ST	R15, RPTSAVE	Save return address
000003A8	5050 81C8	000003C8	295	ST	R5, RPTSVR5	Save R5
			296 *			
			297 *	Use Hercules Diagnose for Message to console		
			298 *			
000003AC	9002 81D0	000003D0	299	STM	R0, R2, RPTDWSAV	save regs used by MSG
000003B0	4520 81E0	000003E0	300	BAL	R2, MSG	call Hercules console MSG display
000003B4	9802 81D0	000003D0	301	LM	R0, R2, RPTDWSAV	restore regs
000003B8	5850 81C8	000003C8	303	L	R5, RPTSVR5	Restore R5
000003BC	58F0 81C4	000003C4	304	L	R15, RPTSAVE	Restore return address
000003C0	07FF		305	BR	R15	Return to caller
000003C4	00000000		307	RPTSAVE DC	F' 0'	R15 save area
000003C8	00000000		308	RPTSVR5 DC	F' 0'	R5 save area
000003D0	00000000 00000000		310	RPTDWSAV DC	2D' 0'	R0-R2 save area for MSG call

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				312 **** 313 * Issue HERCULES MESSAGE pointed to by R1, length in R0 314 * R2 = return address 315 **** 316		
000003E0	4900 82DC		000004DC	317 MSG CH R0, =H' 0' 318 BNHR R2	Do we even HAVE a message? No, ignore	
000003E4	07D2			319		
000003E6	9002 821C		0000041C	320 STM R0, R2, MSGSAVE 321	Save registers	
000003EA	4900 82DE		000004DE	322 CH R0, =AL2(L' MSGMSG)	Message length within limits?	
000003EE	47D0 81F6		000003F6	323 BNH MSGOK	Yes, continue	
000003F2	4100 005F		0000005F	324 LA R0, L' MSGMSG 325	No, set to maximum	
000003F6	1820		00000428	326 MSGOK LR R2, R0 327 BCTR R2, 0 328 EX R2, MSGMVC 329	Copy length to work register Minus-1 for execute Copy message to O/P buffer	
000003F8	0620			330 LA R2, 1+L' MSGCMD(, R2) 331 LA R1, MSGCMD	Calculate true command length Point to true command	
00000402	4420 8228			332		
00000406	83120008		00000416	333 DC X' 83' , X' 12' , X' 0008' 334 BZ MSGRET	Issue Hercules Diagnose X' 008' Return if successful	
0000040A	4780 8216			335		
00000410	1222		00000416	336 LTR R2, R2 337 BZ MSGRET 338	Is Diag8 Ry (R2) 0? an error occurred but continue	
00000410	4780 8216			339 DC H' 0' 340	CRASH for debugging purposes	
00000414	0000		0000041C	341 MSGRET LM R0, R2, MSGSAVE 342 BR R2	Restore registers Return to caller	
0000041C	00000000 00000000		00000437	344 MSGSAVE DC 3F' 0' 00000428 D200 8237 1000 00000000 345 MSGMVC MVC MSGMSG(0), 0(R1)	Registers save area Executed instruction	
0000042E	D4E2C7D5 D6C8405C		00000437	347 MSGCMD DC C' MSGNOH * ' 00000437 40404040 40404040 348 MSGMSG DC CL95' '' 349	*** HERCULES MESSAGE COMMAND *** The message text to be displayed	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				351 **** 352 * Normal completion or Abnormal termination PSWs 353 ****	*****
00000498	00020001 80000000			355 EOJPSW DC OD' 0' , X' 0002000180000000' , AD(0)	
000004A8	B2B2 8298		00000498	357 EOJ LPSWE EOJPSW	Normal completion
000004B0	00020001 80000000			359 FAILPSW DC OD' 0' , X' 0002000180000000' , AD(X' BAD' )	
000004C0	B2B2 82B0		000004B0	361 FAILTEST LPSWE FAILPSW	Abnormal termination
				363 **** 364 * Working Storage 365 ****	*****
000004C4	00000000			367 CTLR0 DS F	CRO
000004C8	00000000			368 DS F	
000004CC				370 LTORG ,	Literals pool
000004CC	00000002			371 =F' 2'	
000004D0	00001990			372 =A(E6TESTS)	
000004D4	00000003			373 =XL4' 3'	
000004D8	00000001			374 =F' 1'	
000004DC	0000			375 =H' 0'	
000004DE	005F			376 =AL2(L' MSGMSG) 377	
				378 * some constants 379	
		00000400	00000001	380 K EQU 1024	One KB
		00001000	00000001	381 PAGE EQU (4*K)	Size of one page
		00010000	00000001	382 K64 EQU (64*K)	64 KB
		00100000	00000001	383 MB EQU (K*K)	1 MB
				384	
				385	
		AABBCCDD	00000001	386 REG2PATT EQU X' AABBCCDD'	Polluted Register pattern
		000000DD	00000001	387 REG2LOW EQU X' DD'	(last byte above)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				389 *=====
				390 *
				391 * NOTE: start data on an address that is easy to display
				392 * within Hercules
				393 *
				394 *=====
000004E0	000004E0	00001000	396	ORG ZVE6TST+X'1000'
00001000	00000000		397	FAILED DC F'0'
00001004	00000000		398	TESTING DC F'0'
				some test failed? current test number
				400 *****
				401 * TEST failed : CC message
				402 *****
				403 *
				404 * failed message and associated editting
				405 *
00001008	40404040 40404040		406 CCPRTLINE DC C' Test # '	
00001018	A7A7A7		407 CCPRTNUM DC C' xxx'	
0000101B	40A69996 95874083		408 DC C' wrong cc for instruction '	
00001035	A7A7A7A7 A7A7A7A7		409 CCPRTNAME DC CL8'xxxxxxxx'	
0000103D	4085A797 8583A385		410 DC C' expected: cc='	
0000104B	A7		411 CCPRTEXP DC C' x'	
0000104C	6B		412 DC C' ,'	
0000104D	40998583 8589A585		413 DC C' received: cc='	
0000105B	A7		414 CCPRTGOT DC C' x'	
0000105C	4B		415 DC C' .'	
		00000055 00000001	416 CCPRTLNG EQU	*-CCPRTLINE



LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				450 **** 451 * E6TEST DSECT 452 ****
00000000	00000000			454 E6TEST DSECT ,
00000004	0000			455 TSUB DC A(0) pointer to test 456 TNUM DC H'00' Test Number
00000006	00			457 DC XL1'00'
00000007	00			458 M3 DC HL1'00' m3
00000008	00			459 CC DC HL1'00' cc
00000009	00			460 CCMASK DC HL1'00' not expected CC mask
0000000A	40404040 40404040			461 462 OPNAME DC CL8' ' E6 name
00000014	00000000			463 464 RELEN DC A(0) RESULT LENGTH 00000018 00000000 DC A(0) expected result address
				466 467 ** 468 * test routine will be here (from VRR_H macro) 469 * followed by 470 * 16-byte v1 source 471 * 16-byte v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
473				*****
474	*			Macros to help build test tables
475	*			- - - - -
476	*			VRR_H Macro to help build test tables
477				*****
478				MACRO
479				VRR_H &INST, &MB, &CC
480	.	*		&INST - instruction under test
481	.	*		&CC - expected CC
482	.	*		
483		LCLA	&XCC(4)	&CC has mask values for FAILED condition codes
484	&XCC(1)	SETA	7	CC != 0
485	&XCC(2)	SETA	11	CC != 1
486	&XCC(3)	SETA	13	CC != 2
487	&XCC(4)	SETA	14	CC != 3
488				
489		GBLA	&TNUM	
490	&TNUM	SETA	&TNUM+1	
491				
492		DS	OFD	
493		USING	*, R5	base for test data and test routine
494				
495	T&TNUM	DC	A(X&TNUM)	address of test routine
496		DC	H' &TNUM	test number
497		DC	XL1' 00'	
498		DC	HL1' &MB'	m3
499		DC	HL1' &CC'	cc
500		DC	HL1' &XCC(&CC+1)'	cc failed mask
501				
502		DC	CL8' &INST'	instruction name
503				
504		DC	A(16)	result length
505	REA&TNUM	DC	A(RE&TNUM)	result address
506	.	*		
507	*			INSTRUCTION UNDER TEST ROUTINE
508	X&TNUM	DS	OF	
509		VL	V1, RE&TNUM	get V1 source
510		VL	V2, RE&TNUM+16	get V2 source
511				
512		&INST	V1, V2, &MB	test instruction
513				
514		EPSW	R2, R0	
515		ST	R2, CCPSW	extract psw to save CC
516				
517		BR	R11	return
518				
519	RE&TNUM	DC	OF	
520		DROP	R5	
521				
522		MEND		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
524				*****
525	*			PTTABLE Macro to generate table of pointers to individual tests
526				*****
527				
528				MACRO
529				PTTABLE
530				GBLA &TNUM
531				LCLA &CUR
532	&CUR			SETA 1
533	. *			
534	TTABLE	DS	OF	
535	. LOOP	ANOP		
536	. *			
537		DC	A(T&CUR)	address of test
538	. *			
539	&CUR	SETA	&CUR+1	
540		AIF	(&CUR LE &TNUM).LOOP	
541	* .			
542		DC	A(0)	END OF TABLE
543		DC	A(0)	
544	. *			
545				MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				547 **** 548 * E6 VRR_H tests 549 ****
00001148		00000000	000019FF	550 ZVE6TST CSECT, 551 DS OF
				553 PRINT DATA 554 * 555 * E677 VCP - VECTOR COMPARE DECIMAL 556 * VRR_H instr, m3, cc 557 * followed by 558 * v1 - 16 byte source 559 * v2 - 16 byte source
				560 * 561 *----- 562 * VCP - VECTOR COMPARE DECIMAL 563 *----- 564 * VCP simple m3= 0 (P1=0, P2=0) 565 * m3= 4 (P1=0, P2=1) 566 * m3= 8 (P1=1, P2=0) 567 * m3=12 (P1=1, P2=1)
00001148	00001164	00001148		568 * m3= 0 (P1=0, P2=0) 569 VRR_H VCP, 0, 0 570+ DS OFD 571+ USING *, R5 572+T1 DC A(X1) base for test data and test routine 573+ DC H' 1' 574+ DC XL1' 00' address of test routine 575+ DC HL1' 0' test number 576+ DC HL1' 0' 577+ DC HL1' 7' 578+ DC CL8' VCP' 579+ DC A(16) 580+REA1 DC A(RE1) 581+* INSTRUCTION UNDER TEST ROUTINE 582+X1 DS OF 583+ VL V1, RE1 584+ VL V2, RE1+16 585+ VCP V1, V2, 0 586+ EPSW R2, R0 587+ ST R2, CCPSW 588+ BR R11 589+RE1 DC OF 590+ DROP R5 591 DC XL16' 00000000000000001234500000000D' V1 source 592 DC XL16' 00000000000000001234500000000D' V2 source 593 594 VRR_H VCP, 0, 0 595+ DS OFD 596+ USING *, R5 597+T2 DC A(X2) 598+ DC H' 2' 599+ DC XL1' 00'
000011A0	000011BC	000011A0		base for test data and test routine address of test routine test number
000011A4	0002			
000011A6	00			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000011A7	00			600+ DC HL1' 0'	m3	
000011A8	00			601+ DC HL1' 0'	cc	
000011A9	07			602+ DC HL1' 7'	cc failed mask	
000011AA	E5C3D740 40404040			603+ DC CL8' VCP'	instruction name	
000011B4	00000010			604+ DC A(16)	result length	
000011B8	000011D8			605+REA2 DC A(RE2)	result address	
				606+* DC	INSTRUCTION UNDER TEST ROUTINE	
				607+X2 DS OF		
000011BC	E710 5038 0006	000011D8		608+ VL V1, RE2	get V1 source	
000011C2	E720 5048 0006	000011E8		609+ VL V2, RE2+16	get V2 source	
000011C8	E601 2000 0077			610+ VCP V1, V2, 0	test instruction	
000011CE	B98D 0020			611+ EPSW R2, R0	extract psw	
000011D2	5020 8E9C	0000109C		612+ ST R2, CCPSW	to save CC	
000011D6	07FB			613+ BR R11	return	
000011D8				614+REA2 DC OF		
000011D8				615+ DROP R5		
000011D8	00000990 00000000			616 DC XL16' 000009900000000000001234500000000C'	V1 source	
000011E0	00123450 0000000C			617 DC XL16' 000009900000000000001234500000000C'	V2 source	
000011E8	00000990 00000000					
000011F0	00123450 0000000C					
				618		
				619 VRR_H VCP, 0, 1		
000011F8		000011F8		620+ DS OFD		
000011F8	00001214			621+ USING *, R5	base for test data and test routine	
000011FC	0003			622+T3 DC A(X3)	address of test routine	
000011FE	00			623+ DC H' 3'	test number	
000011FF	00			624+ DC XL1' 00'		
00001200	01			625+ DC HL1' 0'	m3	
00001200				626+ DC HL1' 1'	cc	
00001201	OB			627+ DC HL1' 11'	cc failed mask	
00001202	E5C3D740 40404040			628+ DC CL8' VCP'	instruction name	
0000120C	00000010			629+ DC A(16)	result length	
00001210	00001230			630+REA3 DC A(RE3)	result address	
				631+* DC	INSTRUCTION UNDER TEST ROUTINE	
				632+X3 DS OF		
00001214	E710 9030 0006	00001230		633+ VL V1, RE3	get V1 source	
0000121A	E720 9040 0006	00001240		634+ VL V2, RE3+16	get V2 source	
00001220	E601 2000 0077			635+ VCP V1, V2, 0	test instruction	
00001226	B98D 0020			636+ EPSW R2, R0	extract psw	
0000122A	5020 8E9C	0000109C		637+ ST R2, CCPSW	to save CC	
0000122E	07FB			638+ BR R11	return	
00001230				639+REA3 DC OF		
00001230				640+ DROP R5		
00001230	00000000 00000000			641 DC XL16' 000000000000000000001234500000000D'	V1 source	
00001238	00123450 0000000D					
00001240	00000000 00000000					
00001248	00123450 0000000C			642 DC XL16' 000000000000000000001234500000000C'	V2 source	
				643		
				644 VRR_H VCP, 0, 1		
00001250		00001250		645+ DS OFD		
00001250	0000126C			646+ USING *, R5	base for test data and test routine	
00001250	0004			647+T4 DC A(X4)	address of test routine	
00001254	0004			648+ DC H' 4'	test number	
00001256	00			649+ DC XL1' 00'		
00001257	00			650+ DC HL1' 0'	m3	
00001258	01			651+ DC HL1' 1'	cc	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001259	OB			652+	DC	HL1' 11'
0000125A	E5C3D740 40404040			653+	DC	CL8' VCP'
00001264	00000010			654+	DC	A(16)
00001268	00001288			655+REA4	DC	A(RE4)
				656+*		
0000126C				657+X4	DS	OF
0000126C	E710 5038 0006	00001288		658+	VL	V1, RE4
00001272	E720 5048 0006	00001298		659+	VL	V2, RE4+16
00001278	E601 2000 0077			660+	VCP	V1, V2, 0
0000127E	B98D 0020			661+	EPSW	R2, R0
00001282	5020 8E9C	0000109C		662+	ST	R2, CCPSW
00001286	07FB			663+	BR	R11
00001288				664+RE4	DC	OF
00001288				665+	DROP	R5
00001288	00000990 00000000			666	DC	XL16' 0000099000000000000000234500000000C'
00001290	00023450 0000000C			667	DC	XL16' 00000990000000000000001234500000000C'
00001298	00000990 00000000					V2 source
000012A0	00123450 0000000C			668		
				669		VRR_H VCP, 0, 2
000012A8				670+	DS	OFD
000012A8	000012C4	000012A8		671+	USING	*, R5
000012A8				672+T5	DC	A(X5)
000012AC	0005			673+	DC	H' 5'
000012AE	00			674+	DC	XL1' 00'
000012AF	00			675+	DC	HL1' 0'
000012B0	02			676+	DC	HL1' 2'
000012B1	0D			677+	DC	HL1' 13'
000012B2	E5C3D740 40404040			678+	DC	CL8' VCP'
000012BC	00000010			679+	DC	A(16)
000012C0	000012E0			680+REA5	DC	A(RE5)
				681+*		
000012C4				682+X5	DS	OF
000012C4	E710 5038 0006	000012E0		683+	VL	V1, RE5
000012CA	E720 5048 0006	000012F0		684+	VL	V2, RE5+16
000012D0	E601 2000 0077			685+	VCP	V1, V2, 0
000012D6	B98D 0020			686+	EPSW	R2, R0
000012DA	5020 8E9C	0000109C		687+	ST	R2, CCPSW
000012DE	07FB			688+	BR	R11
000012E0				689+RE5	DC	OF
000012E0				690+	DROP	R5
000012E0	00000000 00000000			691	DC	XL16' 00000000000000000000001234500000000C'
000012E8	00123450 0000000C			692	DC	XL16' 00000000000000000000001234500000000D'
000012F0	00000000 00000000					V2 source
000012F8	00123450 0000000D			693		
				694		VRR_H VCP, 0, 2
00001300				695+	DS	OFD
00001300	0000131C	00001300		696+	USING	*, R5
00001300				697+T6	DC	A(X6)
00001304	0006			698+	DC	H' 6'
00001306	00			699+	DC	XL1' 00'
00001307	00			700+	DC	HL1' 0'
00001308	02			701+	DC	HL1' 2'
00001309	0D			702+	DC	HL1' 13'
0000130A	E5C3D740 40404040			703+	DC	CL8' VCP'
						cc failed mask instruction name
						result length
						result address
						INSTRUCTION UNDER TEST ROUTINE
						get V1 source
						get V2 source
						test instruction
						extract psw
						to save CC
						return
						m3
						cc
						cc failed mask instruction name
						base for test data and test routine
						address of test routine
						test number
						cc
						cc failed mask instruction name
						base for test data and test routine
						address of test routine
						test number
						m3
						cc
						cc failed mask instruction name

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001314	00000010			704+ DC A(16)	result length	
00001318	00001338			705+REA6 DC A(REA6)	result address	
0000131C				706+*	INSTRUCTION UNDER TEST ROUTINE	
0000131C	E710 5038 0006		00001338	707+X6 DS OF	get V1 source	
00001322	E720 5048 0006		00001348	708+ VL V1, RE6	get V2 source	
00001328	E601 2000 0077			709+ VL V2, RE6+16	test instruction	
0000132E	B98D 0020			710+ VCP V1, V2, 0	extract psw	
00001332	5020 8E9C		0000109C	711+ EPSW R2, R0	to save CC	
00001336	07FB			712+ ST R2, CCPSW	return	
00001338				713+ BR R11		
00001338				714+RE6 DC OF		
00001338	00000990 00000000			715+ DROP R5		
00001340	00123450 0000000C			716 DC XL16' 0000099000000000000012345000000000C'	V1 source	
00001348	00000990 00000000			717 DC XL16' 000009900000000000002345000000000C'	V2 source	
00001350	00023450 0000000C			718		
00001358		00001358		719 * m3= 4 (P1=0, P2=1)		
00001358	00001374			720 VRR_H VCP, 4, 1		
0000135C	0007			721+ DS OFD	base for test data and test routine	
0000135E	00			722+ USING *, R5	address of test routine	
0000135F	04			723+T7 DC A(X7)	test number	
00001360	01			724+ DC H' 7'		
00001361	0B			725+ DC XL1' 00'	m3	
00001362	E5C3D740 40404040			726+ DC HL1' 4'	cc	
0000136C	00000010			727+ DC HL1' 1'	cc failed mask	
00001370	00001390			728+ DC HL1' 11'	instruction name	
00001374				729+ DC CL8' VCP'	result length	
00001374	E710 5038 0006	00001390		730+ DC A(16)	result address	
0000137A	E720 5048 0006	000013A0		731+REA7 DC A(REA7)	INSTRUCTION UNDER TEST ROUTINE	
00001380	E601 2040 0077			732+* DS OF		
00001386	B98D 0020			733+X7 VL V1, RE7	get V1 source	
0000138A	5020 8E9C	0000109C		734+ VL V2, RE7+16	get V2 source	
0000138E	07FB			735+ VCP V1, V2, 4	test instruction	
00001390				736+ EPSW R2, R0	extract psw	
00001390				737+ ST R2, CCPSW	to save CC	
00001390	00000000 00000000			738+ BR R11	return	
00001398	00123450 0000000D			739+ 740+RE7 DC OF		
000013A0	00000000 00000000			741+ DROP R5		
000013A8	00123450 0000000D			742 DC XL16' 000000000000000000001234500000000D'	V1 source	
000013B0				743 DC XL16' 000000000000000000001234500000000D'	V2 source	
000013B0		000013B0		744		
000013B0	000013CC			745 VRR_H VCP, 4, 0		
000013B0	0008			746+ DS OFD	base for test data and test routine	
000013B4				747+ USING *, R5	address of test routine	
000013B6	00			748+T8 DC A(X8)	test number	
000013B7	04			749+ DC H' 8'		
000013B8	00			750+ DC XL1' 00'	m3	
000013B9	07			751+ DC HL1' 4'	cc	
000013BA	E5C3D740 40404040			752+ DC HL1' 0'	cc failed mask	
000013C4	00000010			753+ DC HL1' 7'	instruction name	
				754+ DC CL8' VCP'	result length	
				755+ DC A(16)		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			result address INSTRUCTION UNDER TEST ROUTINE
000013C8	000013E8			756+REA8 757+*	DC	A(REA8)	
000013CC	E710 5038 0006			758+X8	DS	OF	
000013CC	E720 5048 0006	000013E8	000013F8	759+ 760+	VL	V1, RE8 V2, RE8+16	get V1 source get V2 source
000013D8	E601 2040 0077			761+	VCP	V1, V2, 4	test instruction
000013DE	B98D 0020			762+	EPSW	R2, R0	extract psw
000013E2	5020 8E9C		0000109C	763+	ST	R2, CCPSW	to save CC
000013E6	07FB			764+	BR	R11	return
000013E8				765+RE8	DC	OF	
000013E8				766+	DROP	R5	
000013E8	00000990 00000000			767	DC	XL16' 000009900000000000001234500000000C'	V1 source
000013F0	00123450 0000000C			768	DC	XL16' 000009900000000000001234500000000C'	V2 source
00001400	00123450 0000000C			769			
				770	VRR_H	VCP, 4, 1	
00001408			00001408	771+	DS	OFD	
00001408	00001424			772+	USING	* , R5	base for test data and test routine
00001408				773+T9	DC	A(X9)	address of test routine
0000140C	0009			774+	DC	H' 9'	test number
0000140E	00			775+	DC	XL1' 00'	
0000140F	04			776+	DC	HL1' 4'	m3
00001410	01			777+	DC	HL1' 1'	cc
00001411	0B			778+	DC	HL1' 11'	cc failed mask
00001412	E5C3D740 40404040			779+	DC	CL8' VCP'	instruction name
0000141C	00000010			780+	DC	A(16)	result length
00001420	00001440			781+REA9	DC	A(REA9)	result address
				782+*			INSTRUCTION UNDER TEST ROUTINE
00001424				783+X9	DS	OF	
00001424	E710 5038 0006		00001440	784+	VL	V1, RE9	get V1 source
0000142A	E720 5048 0006		00001450	785+	VL	V2, RE9+16	get V2 source
00001430	E601 2040 0077			786+	VCP	V1, V2, 4	test instruction
00001436	B98D 0020			787+	EPSW	R2, R0	extract psw
0000143A	5020 8E9C		0000109C	788+	ST	R2, CCPSW	to save CC
0000143E	07FB			789+	BR	R11	return
00001440				790+RE9	DC	OF	
00001440				791+	DROP	R5	
00001440	00000000 00000000			792	DC	XL16' 000000000000000000001234500000000D'	V1 source
00001448	00123450 0000000D			793	DC	XL16' 000000000000000000001234500000000C'	V2 source
00001450	00000000 00000000			794			
00001458	00123450 0000000C			795	VRR_H	VCP, 4, 1	
00001460			00001460	796+	DS	OFD	
00001460	0000147C			797+	USING	* , R5	base for test data and test routine
00001460				798+T10	DC	A(X10)	address of test routine
00001464	000A			799+	DC	H' 10'	test number
00001466	00			800+	DC	XL1' 00'	
00001467	04			801+	DC	HL1' 4'	m3
00001468	01			802+	DC	HL1' 1'	cc
00001469	0B			803+	DC	HL1' 11'	cc failed mask
0000146A	E5C3D740 40404040			804+	DC	CL8' VCP'	instruction name
00001474	00000010			805+	DC	A(16)	result length
00001478	00001498			806+REA10	DC	A(REA10)	result address
				807+*			INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
0000147C				808+X10	DS	OF
0000147C	E710 5038 0006	00001498	809+	VL	V1, RE10	get V1 source
00001482	E720 5048 0006	000014A8	810+	VL	V2, RE10+16	get V2 source
00001488	E601 2040 0077		811+	VCP	V1, V2, 4	test instruction
0000148E	B98D 0020		812+	EPSW	R2, R0	extract psw
00001492	5020 8E9C	0000109C	813+	ST	R2, CCPSW	to save CC
00001496	07FB		814+	BR	R11	return
00001498			815+RE10	DC	OF	
00001498			816+	DROP	R5	
00001498	00000990 00000000		817	DC	XL16' 00000990000000000000234500000000C'	V1 source
000014A0	00023450 0000000C		818	DC	XL16' 000009900000000000001234500000000C'	V2 source
000014B0	00123450 0000000C		819			
000014B8			820	VRR_H	VCP, 4, 0	
000014B8		000014B8	821+	DS	OFD	
000014B8	000014D4		822+	USING	*, R5	base for test data and test routine
000014BC	000B		823+T11	DC	A(X11)	address of test routine
000014BE	00		824+	DC	H' 11'	test number
000014BF	04		825+	DC	XL1' 00'	
000014C0	00		826+	DC	HL1' 4'	m3
000014C1	07		827+	DC	HL1' 0'	cc
000014C2	E5C3D740 40404040		828+	DC	HL1' 7'	cc failed mask
000014CC	00000010		829+	DC	CL8' VCP'	instruction name
000014D0	000014F0		830+	DC	A(16)	result length
000014D4	E710 5038 0006	000014F0	831+REA11	DC	A(RE11)	result address
000014DA	E720 5048 0006	000014F0	832+*			INSTRUCTION UNDER TEST ROUTINE
000014E0	E601 2040 0077	00001500	834+	VL	V1, RE11	get V1 source
000014E6	B98D 0020	00001500	835+	VL	V2, RE11+16	get V2 source
000014EA	5020 8E9C	0000109C	836+	VCP	V1, V2, 4	test instruction
000014EE	07FB	0000109C	837+	EPSW	R2, R0	extract psw
000014F0			838+	ST	R2, CCPSW	to save CC
000014F0			839+	BR	R11	return
000014F0			840+RE11	DC	OF	
000014F0	00000000 00000000		841+	DROP	R5	
000014F8	00123450 0000000C		842	DC	XL16' 000000000000000000001234500000000C'	V1 source
00001500	00000000 00000000		843	DC	XL16' 000000000000000000001234500000000D'	V2 source
00001508	00123450 0000000D		844			
00001510			845	VRR_H	VCP, 4, 2	
00001510		00001510	846+	DS	OFD	
00001510	0000152C		847+	USING	*, R5	base for test data and test routine
00001514	000C		848+T12	DC	A(X12)	address of test routine
00001516	00		849+	DC	H' 12'	test number
00001517	04		850+	DC	XL1' 00'	
00001518	02		851+	DC	HL1' 4'	m3
00001519	0D		852+	DC	HL1' 2'	cc
0000151A	E5C3D740 40404040		853+	DC	HL1' 13'	cc failed mask
00001524	00000010		854+	DC	CL8' VCP'	instruction name
00001528	00001548		855+	DC	A(16)	result length
0000152C	E710 5038 0006	00001548	856+REA12	DC	A(RE12)	result address
0000152C	E710 5038 0006	00001548	857+*			INSTRUCTION UNDER TEST ROUTINE
0000152C	E710 5038 0006	00001548	858+X12	DS	OF	
0000152C	E710 5038 0006	00001548	859+	VL	V1, RE12	get V1 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001532	E720 5048 0006		00001558	860+ VL V2, RE12+16			
00001538	E601 2040 0077			861+ VCP V1, V2, 4		get V2 source	
0000153E	B98D 0020			862+ EPSW R2, R0		test instruction	
00001542	5020 8E9C		0000109C	863+ ST R2, CCPSW		extract psw	
00001546	07FB			864+ BR R11		to save CC	
00001548				865+RE12 DC OF		return	
00001548				866+ DROP R5			
00001548	00000990 00000000			867 DC XL16' 000009900000000000001234500000000C'		V1 source	
00001550	00123450 0000000C						
00001558	00000990 00000000			868 DC XL16' 00000990000000000000234500000000C'		V2 source	
00001560	00023450 0000000C						
				869			
				870 * m3= 8 (P1=1, P2=0)			
				871 VRR_H VCP, 8, 2			
00001568		00001568		872+ DS OFD			
00001568				873+ USING *, R5		base for test data and test routine	
00001568	00001584			874+T13 DC A(X13)		address of test routine	
0000156C	000D			875+ DC H' 13'		test number	
0000156E	00			876+ DC XL1' 00'			
0000156F	08			877+ DC HL1' 8'		m3	
00001570	02			878+ DC HL1' 2'		cc	
00001571	0D			879+ DC HL1' 13'		cc failed mask	
00001572	E5C3D740 40404040			880+ DC CL8' VCP'		instruction name	
0000157C	00000010			881+ DC A(16)		result length	
00001580	000015A0			882+REA13 DC A(RE13)		result address	
				883+*		INSTRUCTION UNDER TEST ROUTINE	
00001584				884+X13 DS OF			
00001584	E710 5038 0006	000015A0		885+ VL V1, RE13		get V1 source	
0000158A	E720 5048 0006	000015B0		886+ VL V2, RE13+16		get V2 source	
00001590	E601 2080 0077			887+ VCP V1, V2, 8		test instruction	
00001596	B98D 0020			888+ EPSW R2, R0		extract psw	
0000159A	5020 8E9C	0000109C		889+ ST R2, CCPSW		to save CC	
0000159E	07FB			890+ BR R11		return	
000015A0				891+RE13 DC OF			
000015A0				892+ DROP R5			
000015A0	00000000 00000000			893 DC XL16' 000000000000000000001234500000000D'		V1 source	
000015A8	00123450 0000000D						
000015B0	00000000 00000000			894 DC XL16' 000000000000000000001234500000000D'		V2 source	
000015B8	00123450 0000000D						
				895			
				896 VRR_H VCP, 8, 0			
000015C0		000015C0		897+ DS OFD			
000015C0	000015DC			898+ USING *, R5		base for test data and test routine	
000015C0	000015DC			899+T14 DC A(X14)		address of test routine	
000015C4	000E			900+ DC H' 14'		test number	
000015C6	00			901+ DC XL1' 00'			
000015C7	08			902+ DC HL1' 8'		m3	
000015C8	00			903+ DC HL1' 0'		cc	
000015C9	07			904+ DC HL1' 7'		cc failed mask	
000015CA	E5C3D740 40404040			905+ DC CL8' VCP'		instruction name	
000015D4	00000010			906+ DC A(16)		result length	
000015D8	000015F8			907+REA14 DC A(RE14)		result address	
				908+*		INSTRUCTION UNDER TEST ROUTINE	
000015DC	E710 5038 0006	000015F8		909+X14 DS OF			
000015DC	E720 5048 0006	00001608		910+ VL V1, RE14		get V1 source	
000015E2				911+ VL V2, RE14+16		get V2 source	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000015E8	E601 2080 0077			912+ VCP V1, V2, 8			
000015EE	B98D 0020			913+ EPSW R2, R0	test instruction extract psw		
000015F2	5020 8E9C		0000109C	914+ ST R2, CCPSW	to save CC		
000015F6	07FB			915+ BR R11	return		
000015F8				916+RE14 DC OF			
000015F8				917+ DROP R5			
000015F8	00000990 00000000			918 DC XL16' 000009900000000000001234500000000C'	V1 source		
00001600	00123450 0000000C			919 DC XL16' 000009900000000000001234500000000C'	V2 source		
00001608	00000990 00000000			920			
00001610	00123450 0000000C			921 VRR_H VCP, 8, 0			
00001618			00001618	922+ DS OFD			
00001618				923+ USING *, R5	base for test data and test routine		
00001618	00001634			924+T15 DC A(X15)	address of test routine		
0000161C	000F			925+ DC H' 15'	test number		
0000161E	00			926+ DC XL1' 00'			
0000161F	08			927+ DC HL1' 8'	m3		
00001620	00			928+ DC HL1' 0'	cc		
00001621	07			929+ DC HL1' 7'	cc failed mask		
00001622	E5C3D740 40404040			930+ DC CL8' VCP'	instruction name		
0000162C	00000010			931+ DC A(16)	result length		
00001630	00001650			932+REA15 DC A(RE15)	result address		
00001634				933+*	INSTRUCTION UNDER TEST ROUTINE		
00001634	E710 5038 0006		00001650	934+X15 DS OF			
0000163A	E720 5048 0006		00001660	935+ VL V1, RE15	get V1 source		
00001640	E601 2080 0077			936+ VL V2, RE15+16	get V2 source		
00001646	B98D 0020			937+ VCP V1, V2, 8	test instruction		
0000164A	5020 8E9C		0000109C	938+ EPSW R2, R0	extract psw		
0000164E	07FB			939+ ST R2, CCPSW	to save CC		
00001650				940+ BR R11	return		
00001650				941+RE15 DC OF			
00001650	00000000 00000000			942+ DROP R5			
00001658	00123450 0000000D			943 DC XL16' 000000000000000000001234500000000D'	V1 source		
00001660	00000000 00000000			944 DC XL16' 000000000000000000001234500000000C'	V2 source		
00001668	00123450 0000000C			945			
00001670			00001670	946 VRR_H VCP, 8, 1			
00001670				947+ DS OFD			
00001670	0000168C			948+ USING *, R5	base for test data and test routine		
00001674	0010			949+T16 DC A(X16)	address of test routine		
00001676	00			950+ DC H' 16'	test number		
00001677	08			951+ DC XL1' 00'			
00001678	01			952+ DC HL1' 8'	m3		
00001679	0B			953+ DC HL1' 1'	cc		
0000167A	E5C3D740 40404040			954+ DC HL1' 11'	cc failed mask		
00001684	00000010			955+ DC CL8' VCP'	instruction name		
00001688	000016A8			956+ DC A(16)	result length		
00001688				957+REA16 DC A(RE16)	result address		
0000168C				958+*	INSTRUCTION UNDER TEST ROUTINE		
0000168C	E710 5038 0006		000016A8	959+X16 DS OF			
00001692	E720 5048 0006		000016B8	960+ VL V1, RE16	get V1 source		
00001698	E601 2080 0077			961+ VL V2, RE16+16	get V2 source		
0000169E	B98D 0020			962+ VCP V1, V2, 8	test instruction		
0000169E				963+ EPSW R2, R0	extract psw		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000016A2	5020 8E9C		0000109C	964+ 965+ 966+RE16 967+ 968	ST BR DC DROP DC	R2, CCPSW R11 OF R5 XL16' 0000099000000000000000234500000000C'	to save CC return V1 source
000016A6	07FB						
000016A8							
000016A8							
000016A8	00000990 00000000						
000016B0	00023450 0000000C						
000016B8	00000990 00000000			969	DC	XL16' 000009900000000000001234500000000C'	V2 source
000016C0	00123450 0000000C						
				970 971 972+ 973+ 974+T17 975+ 976+ 977+ 978+ 979+ 980+ 981+ 982+REA17 983+* 984+X17	VRR_H DS USING DC DC DC DC DC DC DC DC DC DC A(16) DC	VCP, 8, 2 OFD *, R5 A(X17) H' 17' XL1' 00' HL1' 8' HL1' 2' HL1' 13' CL8' VCP' A(16) A(RE17)	base for test data and test routine address of test routine test number m3 cc cc failed mask instruction name result length result address INSTRUCTION UNDER TEST ROUTINE
000016C8		000016C8					
000016C8	000016E4						
000016C8	0011						
000016CE	00						
000016CF	08						
000016D0	02						
000016D1	0D						
000016D2	E5C3D740 40404040						
000016DC	00000010						
000016E0	00001700						
000016E4	E710 5038 0006	00001700		985+ 986+ 987+ 988+ 989+ 990+	VL VL VCP EPSW ST BR	V1, RE17 V2, RE17+16 V1, V2, 8 R2, R0 R2, CCPSW R11	get V1 source get V2 source test instruction extract psw to save CC return
000016EA	E720 5048 0006	00001710					
000016F0	E601 2080 0077						
000016F6	B98D 0020						
000016FA	5020 8E9C	0000109C					
000016FE	07FB						
00001700				991+RE17	DC	OF	
00001700				992+	DROP	R5	
00001700	00000000 00000000			993	DC	XL16' 000000000000000000001234500000000C'	V1 source
00001708	00123450 0000000C						
00001710	00000000 00000000			994	DC	XL16' 000000000000000000001234500000000D'	V2 source
00001718	00123450 0000000D						
00001720		00001720		995 996 997+	VRR_H DS	VCP, 8, 2 OFD	
00001720	0000173C			998+ 999+T18	USING DC	*, R5 A(X18)	base for test data and test routine address of test routine test number
00001724	0012			1000+	DC	H' 18'	
00001726	00			1001+	DC	XL1' 00'	
00001727	08			1002+	DC	HL1' 8'	m3
00001728	02			1003+	DC	HL1' 2'	cc
00001729	0D			1004+	DC	HL1' 13'	cc failed mask
0000172A	E5C3D740 40404040			1005+	DC	CL8' VCP'	instruction name
00001734	00000010			1006+	DC	A(16)	result length
00001738	00001758			1007+REA18	DC	A(RE18)	result address
0000173C				1008+* 1009+X18	DS	OF	INSTRUCTION UNDER TEST ROUTINE
0000173C	E710 5038 0006	00001758		1010+	VL	V1, RE18	get V1 source
00001742	E720 5048 0006	00001768		1011+	VL	V2, RE18+16	get V2 source
00001748	E601 2080 0077			1012+	VCP	V1, V2, 8	test instruction
0000174E	B98D 0020			1013+	EPSW	R2, R0	extract psw
00001752	5020 8E9C	0000109C		1014+	ST	R2, CCPSW	to save CC
00001756	07FB			1015+	BR	R11	return

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001758				1016+RE18	DC	OF
00001758				1017+	DROP	R5
00001758	00000990 00000000			1018	DC	XL16' 000009900000000000001234500000000C'
00001760	00123450 0000000C					V1 source
00001768	00000990 00000000			1019	DC	XL16' 00000990000000000000234500000000C'
00001770	00023450 0000000C					V2 source
				1020		
				1021 * m3=12	(P1=1, P2=1)	
				1022	VRR_H	VCP, 12, 0
00001778				1023+	DS	OFD
00001778		00001778		1024+	USING	* , R5
00001778	00001794			1025+T19	DC	A(X19)
0000177C	0013			1026+	DC	H' 19'
0000177E	00			1027+	DC	XL1' 00'
0000177F	0C			1028+	DC	HL1' 12'
00001780	00			1029+	DC	HL1' 0'
00001781	07			1030+	DC	HL1' 7'
00001782	E5C3D740 40404040			1031+	DC	CL8' VCP'
0000178C	00000010			1032+	DC	A(16)
00001790	000017B0			1033+REA19	DC	A(REA19)
				1034+*		INSTRUCTION UNDER TEST ROUTINE
00001794				1035+X19	DS	OF
00001794	E710 5038 0006		000017B0	1036+	VL	V1, RE19
0000179A	E720 5048 0006		000017C0	1037+	VL	V2, RE19+16
000017A0	E601 20C0 0077			1038+	VCP	V1, V2, 12
000017A6	B98D 0020			1039+	EPSW	R2, R0
000017AA	5020 8E9C		0000109C	1040+	ST	R2, CCPSW
000017AE	07FB			1041+	BR	R11
000017B0				1042+RE19	DC	OF
000017B0				1043+	DROP	R5
000017B0	00000000 00000000			1044	DC	XL16' 000000000000000000001234500000000D'
000017B8	00123450 0000000D					V1 source
000017C0	00000000 00000000			1045	DC	XL16' 000000000000000000001234500000000D'
000017C8	00123450 0000000D					V2 source
				1046		
000017D0				1047	VRR_H	VCP, 12, 0
000017D0				1048+	DS	OFD
000017D0		000017D0		1049+	USING	* , R5
000017D0	000017EC			1050+T20	DC	A(X20)
000017D4	0014			1051+	DC	H' 20'
000017D6	00			1052+	DC	XL1' 00'
000017D7	0C			1053+	DC	HL1' 12'
000017D8	00			1054+	DC	HL1' 0'
000017D9	07			1055+	DC	HL1' 7'
000017DA	E5C3D740 40404040			1056+	DC	CL8' VCP'
000017E4	00000010			1057+	DC	A(16)
000017E8	00001808			1058+REA20	DC	A(REA20)
				1059+*		INSTRUCTION UNDER TEST ROUTINE
000017EC				1060+X20	DS	OF
000017EC	E710 5038 0006		00001808	1061+	VL	V1, RE20
000017F2	E720 5048 0006		00001818	1062+	VL	V2, RE20+16
000017F8	E601 20C0 0077			1063+	VCP	V1, V2, 12
000017FE	B98D 0020			1064+	EPSW	R2, R0
00001802	5020 8E9C		0000109C	1065+	ST	R2, CCPSW
00001806	07FB			1066+	BR	R11
00001808				1067+RE20	DC	OF

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001808				1068+	DROP	R5	
00001808	00000990 00000000			1069	DC	XL16' 000009900000000000001234500000000C'	V1 source
00001810	00123450 0000000C						
00001818	00000990 00000000			1070	DC	XL16' 000009900000000000001234500000000C'	V2 source
00001820	00123450 0000000C						
				1071			
				1072	VRR_H	VCP, 12, 0	
				1073+	DS	OFD	
00001828		00001828		1074+	USING	*, R5	base for test data and test routine
00001828	00001844			1075+T21	DC	A(X21)	address of test routine
0000182C	0015			1076+	DC	H' 21'	test number
0000182E	00			1077+	DC	XL1' 00'	
0000182F	0C			1078+	DC	HL1' 12'	m3
00001830	00			1079+	DC	HL1' 0'	cc
00001831	07			1080+	DC	HL1' 7'	cc failed mask
00001832	E5C3D740 40404040			1081+	DC	CL8' VCP'	instruction name
0000183C	00000010			1082+	DC	A(16)	result length
00001840	00001860			1083+REA21	DC	A(RE21)	result address
				1084+*			INSTRUCTION UNDER TEST ROUTINE
				1085+X21	DS	OF	
00001844	E710 5038 0006	00001860		1086+	VL	V1, RE21	get V1 source
0000184A	E720 5048 0006	00001870		1087+	VL	V2, RE21+16	get V2 source
00001850	E601 20C0 0077			1088+	VCP	V1, V2, 12	test instruction
00001856	B98D 0020			1089+	EPSW	R2, R0	extract psw
0000185A	5020 8E9C	0000109C		1090+	ST	R2, CCPSW	to save CC
0000185E	07FB			1091+	BR	R11	return
00001860				1092+RE21	DC	OF	
00001860				1093+	DROP	R5	
00001860	00000000 00000000			1094	DC	XL16' 000000000000000000001234500000000D'	V1 source
00001868	00123450 0000000D			1095	DC	XL16' 000000000000000000001234500000000C'	V2 source
00001870	00000000 00000000						
00001878	00123450 0000000C						
				1096			
				1097	VRR_H	VCP, 12, 1	
				1098+	DS	OFD	
00001880		00001880		1099+	USING	*, R5	base for test data and test routine
00001880	0000189C			1100+T22	DC	A(X22)	address of test routine
00001884	0016			1101+	DC	H' 22'	test number
00001886	00			1102+	DC	XL1' 00'	
00001887	0C			1103+	DC	HL1' 12'	m3
00001888	01			1104+	DC	HL1' 1'	cc
00001889	0B			1105+	DC	HL1' 11'	cc failed mask
0000188A	E5C3D740 40404040			1106+	DC	CL8' VCP'	instruction name
00001894	00000010			1107+	DC	A(16)	result length
00001898	000018B8			1108+REA22	DC	A(RE22)	result address
				1109+*			INSTRUCTION UNDER TEST ROUTINE
				1110+X22	DS	OF	
0000189C	E710 5038 0006	000018B8		1111+	VL	V1, RE22	get V1 source
000018A2	E720 5048 0006	000018C8		1112+	VL	V2, RE22+16	get V2 source
000018A8	E601 20C0 0077			1113+	VCP	V1, V2, 12	test instruction
000018AE	B98D 0020			1114+	EPSW	R2, R0	extract psw
000018B2	5020 8E9C	0000109C		1115+	ST	R2, CCPSW	to save CC
000018B6	07FB			1116+	BR	R11	return
000018B8				1117+RE22	DC	OF	
000018B8				1118+	DROP	R5	
000018B8	00000990 00000000			1119	DC	XL16' 00000990000000000000234500000000C'	V1 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000018C0	00023450 0000000C			1120	DC	XL16' 0000099000000000000012345000000000C' V2 source
000018C8	00000990 00000000			1121		
000018D0	00123450 0000000C			1122	VRR_H	VCP, 12, 0
000018D8				1123+	DS	OFD
000018D8		000018D8		1124+	USING	*, R5
000018D8	000018F4			1125+T23	DC	A(X23)
000018DC	0017			1126+	DC	H' 23'
000018DE	00			1127+	DC	XL1' 00'
000018DF	0C			1128+	DC	HL1' 12'
000018E0	00			1129+	DC	HL1' 0'
000018E1	07			1130+	DC	HL1' 7'
000018E2	E5C3D740 40404040			1131+	DC	CL8' VCP'
000018EC	00000010			1132+	DC	A(16)
000018F0	00001910			1133+REA23	DC	A(REA23)
				1134+*		INSTRUCTION UNDER TEST ROUTINE
000018F4				1135+X23	DS	OF
000018F4	E710 5038 0006		00001910	1136+	VL	V1, RE23
000018FA	E720 5048 0006		00001920	1137+	VL	V2, RE23+16
00001900	E601 20C0 0077			1138+	VCP	V1, V2, 12
00001906	B98D 0020			1139+	EPSW	R2, R0
0000190A	5020 8E9C		0000109C	1140+	ST	R2, CCPSW
0000190E	07FB			1141+	BR	R11
00001910				1142+RE23	DC	OF
00001910				1143+	DROP	R5
00001910	00000000 00000000			1144	DC	XL16' 000000000000000000001234500000000C' V1 source
00001918	00123450 0000000C			1145	DC	XL16' 000000000000000000001234500000000D' V2 source
00001920	00000000 00000000					
00001928	00123450 0000000D					
				1146		
				1147	VRR_H	VCP, 12, 2
00001930				1148+	DS	OFD
00001930		00001930		1149+	USING	*, R5
00001930	0000194C			1150+T24	DC	A(X24)
00001934	0018			1151+	DC	H' 24'
00001936	00			1152+	DC	XL1' 00'
00001937	0C			1153+	DC	HL1' 12'
00001938	02			1154+	DC	HL1' 2'
00001939	0D			1155+	DC	HL1' 13'
0000193A	E5C3D740 40404040			1156+	DC	CL8' VCP'
00001944	00000010			1157+	DC	A(16)
00001948	00001968			1158+REA24	DC	A(REA24)
				1159+*		INSTRUCTION UNDER TEST ROUTINE
0000194C				1160+X24	DS	OF
0000194C	E710 5038 0006		00001968	1161+	VL	V1, RE24
00001952	E720 5048 0006		00001978	1162+	VL	V2, RE24+16
00001958	E601 20C0 0077			1163+	VCP	V1, V2, 12
0000195E	B98D 0020			1164+	EPSW	R2, R0
00001962	5020 8E9C		0000109C	1165+	ST	R2, CCPSW
00001966	07FB			1166+	BR	R11
00001968				1167+RE24	DC	OF
00001968				1168+	DROP	R5
00001968	00000990 00000000			1169	DC	XL16' 000009900000000000001234500000000C' V1 source
00001970	00123450 0000000C			1170	DC	XL16' 00000990000000000000234500000000C' V2 source
00001978	00000990 00000000					

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
00001980	00023450	0000000C		1171
00001988	00000000		1172	DC F' 0' END OF TABLE
0000198C	00000000		1173	DC F' 0'
			1174 *	
			1175	* table of pointers to individual load test
			1176 *	
00001990			1177	E6TESTS DS OF
			1178	PTTABLE
00001990	00001148		1179+TTABLE	DS OF
00001990	000011A0		1180+	DC A(T1) address of test
00001994	000011A0		1181+	DC A(T2) address of test
00001998	000011F8		1182+	DC A(T3) address of test
0000199C	00001250		1183+	DC A(T4) address of test
000019A0	000012A8		1184+	DC A(T5) address of test
000019A4	00001300		1185+	DC A(T6) address of test
000019A8	00001358		1186+	DC A(T7) address of test
000019AC	000013B0		1187+	DC A(T8) address of test
000019B0	00001408		1188+	DC A(T9) address of test
000019B4	00001460		1189+	DC A(T10) address of test
000019B8	000014B8		1190+	DC A(T11) address of test
000019BC	00001510		1191+	DC A(T12) address of test
000019C0	00001568		1192+	DC A(T13) address of test
000019C4	000015C0		1193+	DC A(T14) address of test
000019C8	00001618		1194+	DC A(T15) address of test
000019CC	00001670		1195+	DC A(T16) address of test
000019D0	000016C8		1196+	DC A(T17) address of test
000019D4	00001720		1197+	DC A(T18) address of test
000019D8	00001778		1198+	DC A(T19) address of test
000019DC	000017D0		1199+	DC A(T20) address of test
000019E0	00001828		1200+	DC A(T21) address of test
000019E4	00001880		1201+	DC A(T22) address of test
000019E8	000018D8		1202+	DC A(T23) address of test
000019EC	00001930		1203+	DC A(T24) address of test
			1204+*	
000019F0	00000000		1205+	DC A(0) END OF TABLE
000019F4	00000000		1206+	DC A(0)
			1207	
000019F8	00000000		1208	DC F' 0' END OF TABLE
000019FC	00000000		1209	DC F' 0'

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				1211 *****	*****
				1212 *	Register equates
				1213 *****	*****
	00000000	00000001	1215 R0	EQU	0
	00000001	00000001	1216 R1	EQU	1
	00000002	00000001	1217 R2	EQU	2
	00000003	00000001	1218 R3	EQU	3
	00000004	00000001	1219 R4	EQU	4
	00000005	00000001	1220 R5	EQU	5
	00000006	00000001	1221 R6	EQU	6
	00000007	00000001	1222 R7	EQU	7
	00000008	00000001	1223 R8	EQU	8
	00000009	00000001	1224 R9	EQU	9
	0000000A	00000001	1225 R10	EQU	10
	0000000B	00000001	1226 R11	EQU	11
	0000000C	00000001	1227 R12	EQU	12
	0000000D	00000001	1228 R13	EQU	13
	0000000E	00000001	1229 R14	EQU	14
	0000000F	00000001	1230 R15	EQU	15
				1232 *****	*****
				1233 *	Register equates
				1234 *****	*****
	00000000	00000001	1236 V0	EQU	0
	00000001	00000001	1237 V1	EQU	1
	00000002	00000001	1238 V2	EQU	2
	00000003	00000001	1239 V3	EQU	3
	00000004	00000001	1240 V4	EQU	4
	00000005	00000001	1241 V5	EQU	5
	00000006	00000001	1242 V6	EQU	6
	00000007	00000001	1243 V7	EQU	7
	00000008	00000001	1244 V8	EQU	8
	00000009	00000001	1245 V9	EQU	9
	0000000A	00000001	1246 V10	EQU	10
	0000000B	00000001	1247 V11	EQU	11
	0000000C	00000001	1248 V12	EQU	12
	0000000D	00000001	1249 V13	EQU	13
	0000000E	00000001	1250 V14	EQU	14
	0000000F	00000001	1251 V15	EQU	15
	00000010	00000001	1252 V16	EQU	16
	00000011	00000001	1253 V17	EQU	17
	00000012	00000001	1254 V18	EQU	18
	00000013	00000001	1255 V19	EQU	19
	00000014	00000001	1256 V20	EQU	20
	00000015	00000001	1257 V21	EQU	21

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
		00000016	00000001	1258 V22	EQU	22
		00000017	00000001	1259 V23	EQU	23
		00000018	00000001	1260 V24	EQU	24
		00000019	00000001	1261 V25	EQU	25
		0000001A	00000001	1262 V26	EQU	26
		0000001B	00000001	1263 V27	EQU	27
		0000001C	00000001	1264 V28	EQU	28
		0000001D	00000001	1265 V29	EQU	29
		0000001E	00000001	1266 V30	EQU	30
		0000001F	00000001	1267 V31	EQU	31
				1268		
				1269	END	





SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
REA23	A	000018F0	4	1133	
REA24	A	00001948	4	1158	
REA3	A	00001210	4	630	
REA4	A	00001268	4	655	
REA5	A	000012C0	4	680	
REA6	A	00001318	4	705	
REA7	A	00001370	4	731	
REA8	A	000013C8	4	756	
REA9	A	00001420	4	781	
READDR	A	00000018	4	465	
REG2LOW	U	000000DD	1	387	
REG2PATT	U	AABBCCDD	1	386	
RELEN	A	00000014	4	464	
RPTDWSAV	D	000003D0	8	310	299 301
RPTERROR	I	000003A4	4	294	264
RPTSAVE	F	000003C4	4	307	294 304
RPTSVR5	F	000003C8	4	308	295 303
SKL0001	U	00000054	1	176	192
SKT0001	C	0000022A	26	173	176 193
SVOLDPSW	U	00000140	0	111	
T1	A	00001148	4	572	1180
T10	A	00001460	4	798	1189
T11	A	000014B8	4	823	1190
T12	A	00001510	4	848	1191
T13	A	00001568	4	874	1192
T14	A	000015C0	4	899	1193
T15	A	00001618	4	924	1194
T16	A	00001670	4	949	1195
T17	A	000016C8	4	974	1196
T18	A	00001720	4	999	1197
T19	A	00001778	4	1025	1198
T2	A	000011A0	4	597	1181
T20	A	000017D0	4	1050	1199
T21	A	00001828	4	1075	1200
T22	A	00001880	4	1100	1201
T23	A	000018D8	4	1125	1202
T24	A	00001930	4	1150	1203
T3	A	000011F8	4	622	1182
T4	A	00001250	4	647	1183
T5	A	000012A8	4	672	1184
T6	A	00001300	4	697	1185
T7	A	00001358	4	723	1186
T8	A	000013B0	4	748	1187
T9	A	00001408	4	773	1188
TESTCC	I	00000306	4	223	218
TESTING	F	00001004	4	398	
TNUM	H	00000004	2	456	240
TSUB	A	00000000	4	455	213
TTABLE	F	00001990	4	1179	
V0	U	00000000	1	1236	
V1	U	00000001	1	1237	583 585 608 610 633 635 658 660 683 685 708 710 734 736 759 761 784 786 809 811 834 836 859 861 885 887 910 912 935 937 960 962 985 987 1010 1012 1036 1038 1061
V10	U	0000000A	1	1246	
V11	U	0000000B	1	1247	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
V12	U	0000000C	1	1248	
V13	U	0000000D	1	1249	
V14	U	0000000E	1	1250	
V15	U	0000000F	1	1251	
V16	U	00000010	1	1252	
V17	U	00000011	1	1253	
V18	U	00000012	1	1254	
V19	U	00000013	1	1255	
V1FUDGE	X	000010F8	16	443	
V1FUDGEB	X	00001108	16	444	
V1INPUT	C	00001118	16	445	
V1OUTPUT	X	000010C0	16	439	
V2	U	00000002	1	1238	584 585 609 610 634 635 659 660 684 685 709 710 735 736 760 761 785 786 810 811 835 836 860 861 886 887 911 912 936 937 961 962 986 987 1011 1012 1037 1038 1062 1063 1087 1088 1112 1113 1137 1138 1162 1163
V20	U	00000014	1	1256	
V21	U	00000015	1	1257	
V22	U	00000016	1	1258	
V23	U	00000017	1	1259	
V24	U	00000018	1	1260	
V25	U	00000019	1	1261	
V26	U	0000001A	1	1262	
V27	U	0000001B	1	1263	
V28	U	0000001C	1	1264	
V29	U	0000001D	1	1265	
V3	U	00000003	1	1239	
V30	U	0000001E	1	1266	
V31	U	0000001F	1	1267	
V4	U	00000004	1	1240	
V5	U	00000005	1	1241	
V6	U	00000006	1	1242	
V7	U	00000007	1	1243	
V8	U	00000008	1	1244	
V9	U	00000009	1	1245	
X0001	U	000002B0	1	182 170 183	
X1	F	00001164	4	582 572	
X10	F	0000147C	4	808 798	
X11	F	000014D4	4	833 823	
X12	F	0000152C	4	858 848	
X13	F	00001584	4	884 874	
X14	F	000015DC	4	909 899	
X15	F	00001634	4	934 924	
X16	F	0000168C	4	959 949	
X17	F	000016E4	4	984 974	
X18	F	0000173C	4	1009 999	
X19	F	00001794	4	1035 1025	
X2	F	000011BC	4	607 597	
X20	F	000017EC	4	1060 1050	
X21	F	00001844	4	1085 1075	
X22	F	0000189C	4	1110 1100	
X23	F	000018F4	4	1135 1125	
X24	F	0000194C	4	1160 1150	
X3	F	00001214	4	632 622	
X4	F	0000126C	4	657 647	
X5	F	000012C4	4	682 672	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
X6	F	0000131C	4	707	697
X7	F	00001374	4	733	723
X8	F	000013CC	4	758	748
X9	F	00001424	4	783	773
XC0001	U	000002D8	1	196	188
ZVE6TST	J	00000000	6656	108	111 113 117 121 396 109
=A(E6TESTS)	A	000004D0	4	372	202
=AL2(L' MSGMSG)	R	000004DE	2	376	322
=F' 1'	F	000004D8	4	374	272
=F' 2'	F	000004CC	4	371	187
=H' 0'	H	000004DC	2	375	317
=XL4' 3'	X	000004D4	4	373	235

MACRO	DEFN	REFERENCES
FCHECK	60	169
PTTABLE	529	1178
VRR_H	479	569 996
		594 1022
		619 1047
		644 1072
		669 1097
		694 1122
		720 1147
		745
		770
		795
		820
		845
		871
		896
		921
		946
		971

DESC	SYMBOL	SIZE	POS	ADDI
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**Entry:** 0

<b>Image</b>	<b>IMAGE</b>	<b>6656</b>	<b>0000-19FF</b>	<b>0000-19FF</b>
<b>Region</b>		<b>6656</b>	<b>0000-19FF</b>	<b>0000-19FF</b>
<b>CSECT</b>	<b>ZVE6TST</b>	<b>6656</b>	<b>0000-19FF</b>	<b>0000-19FF</b>

STMT	FILE NAME
1	/home/tn529/sharedvfp/tests/zvector-e6-15-comparedecimal.asm

\*\* NO ERRORS FOUND \*\*